

ABSTRACT OF THE DISCLOSURE

A method of detecting spatially correlated variations that may be used for detecting statistical
5 outliers in a production lot of integrated circuits to
increase the average service life of the production lot
includes measuring a selected parameter of each of a
plurality of electronic circuits replicated on a common
surface; calculating a difference between a value of the
10 selected parameter at a target location and a value of the
selected parameter an identical relative location with
respect to the target location for each of the plurality of
electronic circuits to generate a distribution of
differences; calculating an absolute value of the
15 distribution of differences; and calculating an average of
the absolute value of the distribution of differences to
generate a representative value for the residual for the
identical relative location.